

INCH-POUND

MIL-M-38510/40B  
2 December 2005  
SUPERSEDING  
MIL-M-38510/40A  
13 April 1984

## MILITARY SPECIFICATION

MICROCIRCUITS, DIGITAL, TTL, HIGH SPEED,  
AND-OR-INVERT GATES, MONOLITHIC SILICON

Inactive for new design after 13 April 1984.

This specification is approved for use by all Departments  
and Agencies of the Department of Defense.

The requirements for acquiring the product herein shall consist of this specification sheet and MIL-PRF 38535

### 1. SCOPE

1.1 Scope. This specification covers the detail requirements for monolithic silicon, TTL, HIGH SPEED, AND-OR-INVERT logic gating microcircuits. One product assurance class and a choice of case outlines and lead finishes are provided for each type and are reflected in the complete part number.

1.2 Part or Identifying Number (PIN). The PIN is in accordance with MIL-PRF-38535.

1.2.1 Device types. The device types are as follows:

<u>Device type</u>	<u>Circuit</u>
01	Expandable dual 2-wide, 2-input AND-OR-INVERT gate
02	Dual 2-wide, 2-input AND-OR-INVERT gate
03	Expandable 2-2-2-3 input AND-OR-INVERT gate
04	2-2-2-3 input AND-OR-INVERT gate
05	Expandable 2-wide, 4-input AND-OR-INVERT gate

1.2.2 Device class. The device class is the product assurance level as defined in MIL-PRF-38535.

1.2.3 Case outlines. The case outlines are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
A	GDFP5-F14 or CDFP6-F14	14	Flat pack
B	GDFP4-F14	14	Flat pack
C	GDIP1-T14 or CDIP2-T14	14	Dual-in-line
D	GDFP1-F14 or CDFP2-F14	14	Flat pack

Comments, suggestions, or questions on this document should be addressed to: Commander, Defense Supply Center Columbus, ATTN: DSCC-VAS, P. O. Box 3990, Columbus, OH 43218-3990, or emailed to [bipolar@dsccl.dla.mil](mailto:bipolar@dsccl.dla.mil). Since contact information can change, you may want to verify the currency of this address information using the ASSIST Online database at <http://assist.daps.dla.mil>.

1.3 Absolute maximum ratings.

Supply voltage range .....	-0.5 V dc to +7.0 V dc
Input voltage range .....	-1.5 V dc at -12 mA to +5.5 V dc
Storage temperature range .....	-65°C to 150°C
Maximum power dissipation per device (P <sub>D</sub> ): 1/	
Device types 01, 02, 03, and 04 .....	140 mW
Device type 05 .....	75 mW
Lead temperature (soldering, 10 seconds) .....	+300°C
Thermal resistance, junction-to-case (θ <sub>JC</sub> ): .....	(See MIL-STD-1835)
Junction temperature (T <sub>J</sub> ) .....	+175°C

1.4 Recommended operating conditions.

Supply voltage (V <sub>CC</sub> ) .....	4.5 V dc minimum to 5.5 V dc maximum
Minimum high level input voltage (V <sub>IH</sub> ) .....	2.0 V dc
Maximum low level input voltage (V <sub>IL</sub> ) .....	0.8 V dc
Normalized fanout (each output) 2/ .....	10 maximum
Case operating temperature range (T <sub>C</sub> ) .....	-55°C to +125°C

## 2. APPLICABLE DOCUMENTS

2.1 General. The documents listed in this section are specified in sections 3, 4, or 5 of this specification. This section does not include documents cited in other sections of this specification or recommended for additional information or as examples. While every effort has been made to ensure the completeness of this list, document users are cautioned that they must meet all specified requirements of documents cited in sections 3, 4, or 5 of this specification, whether or not they are listed.

2.2 Government documents.

2.2.1 Specifications and standards. The following specifications and standards form a part of this specification to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

## DEPARTMENT OF DEFENSE SPECIFICATIONS

MIL-PRF-38535 - Integrated Circuits (Microcircuits) Manufacturing, General Specification for.

## DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard for Microelectronics.  
MIL-STD-1835 - Interface Standard Electronic Component Case Outlines

(Copies of these documents are available online at <http://assist.daps.dla.mil/quicksearch/> or <http://assist.daps.dla.mil> or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.3 Order of precedence. In the event of a conflict between the text of this specification and the references cited herein, the text of this document takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

1/ Must withstand the added PD due to short circuit condition (e.g., I<sub>OS</sub>) at one output for 5 seconds duration.

2/ Device will fanout in both high and low levels to the specified number of inputs of the same device type as that being tested.

### 3. REQUIREMENTS

3.1 Qualification. Microcircuits furnished under this specification shall be products that are manufactured by a manufacturer authorized by the qualifying activity for listing on the applicable qualified manufacturers list before contract award (see 4.3 and 6.3).

3.2 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

3.3 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein.

3.3.1 Case outlines. The case outlines shall be as specified in 1.2.3.

3.3.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.3.3 Logic diagram. The logic diagram connections shall be as specified on figure 1.

3.3.4 Truth tables. The truth tables shall be as specified on figure 2.

3.4 Lead material and finish. The lead material and finish shall be in accordance with MIL-PRF-38535 (see 6.6).

3.5 Electrical performance characteristics. The electrical performance characteristics are as specified in table I, and apply over the full recommended case operating temperature range, unless otherwise specified.

3.6 Electrical test requirements. The electrical test requirements for each device class shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table III.

3.7 Marking. Marking shall be in accordance with MIL-PRF-38535.

3.8 Microcircuit group assignment. The devices covered by this specification shall be in microcircuit group number 1 (see MIL-PRF-38535, appendix A).

### 4. VERIFICATION

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not effect the form, fit, or function as described herein.

4.2 Screening. Screening shall be in accordance with MIL-PRF-38535 and shall be conducted on all devices prior to qualification and conformance inspection. The following additional criteria shall apply:

- a. The burn-in test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table II, except interim electrical parameters test prior to burn-in is optional at the discretion of the manufacturer.

4.3 Qualification inspection. Qualification inspection shall be in accordance with MIL-PRF-38535.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C unless otherwise specified	Device type	Limits		Unit
				Min	Max	
High level output voltage	V <sub>OH</sub>	V <sub>CC</sub> = 4.5 V, V <sub>IN</sub> = 0.8 V, I <sub>OH</sub> = -500 μA <u>1/</u>	All	2.4		V
Low level output voltage	V <sub>OL</sub>	V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 20 mA, V <sub>IN</sub> = 2.0 V for all inputs of gate under test	All		0.4	V
Input clamp voltage	V <sub>IC</sub>	V <sub>CC</sub> = 4.5 V, I <sub>IN</sub> = -12 mA, T <sub>C</sub> = +25°C	All		-1.5	V
High level input current	I <sub>IH1</sub>	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 2.4 V <u>2/</u>	All		50	μA
	I <sub>IH2</sub>	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 5.5 V <u>2/</u>	All		100	μA
Low level input current	I <sub>IL</sub>	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 0.4 V <u>1/</u>	All	-1.0	-2.0	mA
Short circuit output current	I <sub>OS</sub>	V <sub>CC</sub> = 5.5 V <u>2/</u> , <u>3/</u>	All	-40	-100	mA
High level supply current	I <sub>CCH</sub>	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 0 V <u>2/</u>	01, 02		13	mA
			03, 04		11	
			05		6.4	
Low level supply current	I <sub>CCL</sub>	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 5.5 V <u>1/</u>	01, 02		24	mA
			03, 04		14	
			05		12	
Expander input current	I <sub>X</sub>	V <sub>CC</sub> = 4.5 V, V <sub>IN</sub> = 1.4 V	01, 03, 05		-5.85	mA
Base emitter voltage of output transistor	V <sub>BE</sub>	V <sub>CC</sub> = 4.5 V, I <sub>OL</sub> = 20 mA, I <sub>X</sub> = 700 μA	01, 03, 05		1.1	V
Propagation delay time, high to low level expander pins open	t <sub>PHL1</sub>	C <sub>L</sub> = 50 pF, R <sub>L</sub> = 280 Ω	All	2	18	ns
Propagation delay time, low to high level expander pins open	t <sub>PLH1</sub>	C <sub>L</sub> = 50 pF, R <sub>L</sub> = 280 Ω	All	2	18	ns
Propagation delay time, high to low level	t <sub>PHL2</sub>	C <sub>L</sub> = 50 pF, R <sub>L</sub> = 280 Ω C <sub>X̄</sub> = 15 pF	01, 03, 05	2	22	ns
Propagation delay time, low to high level	t <sub>PLH2</sub>	C <sub>L</sub> = 50 pF, R <sub>L</sub> = 280 Ω C <sub>X̄</sub> = 15 pF	01, 03, 05	2	26	ns

1/ All unspecified inputs at 5.5 volts.2/ All unspecified inputs grounded.3/ Not more than one output should be shorted at a time.

TABLE II. Electrical test requirements.

MIL-PRF-38535 test requirements	Subgroup (see table III)
	Class B devices
Interim electrical parameters	1
Final electrical test parameters	1*, 2, 3, 9
Group A test requirements	1, 2, 3, 9
Group B electrical test parameters when using the method 5005 QCI option	N/A
Group C end-point electrical parameters	1, 2, 3
Additional electrical subgroups for group C periodic inspections	10, 11
Group D end-point electrical parameters	1, 2, 3

\*PDA applies to subgroup 1.

4.4 Technology Conformance Inspection (TCI). Technology conformance inspection shall be in accordance with MIL-PRF-38535 and herein for groups A, B, C, and D inspections (see 4.4.1 through 4.4.4).

4.4.1 Group A inspection. Group A inspection shall be in accordance with table III of MIL-PRF-38535 and as follows:

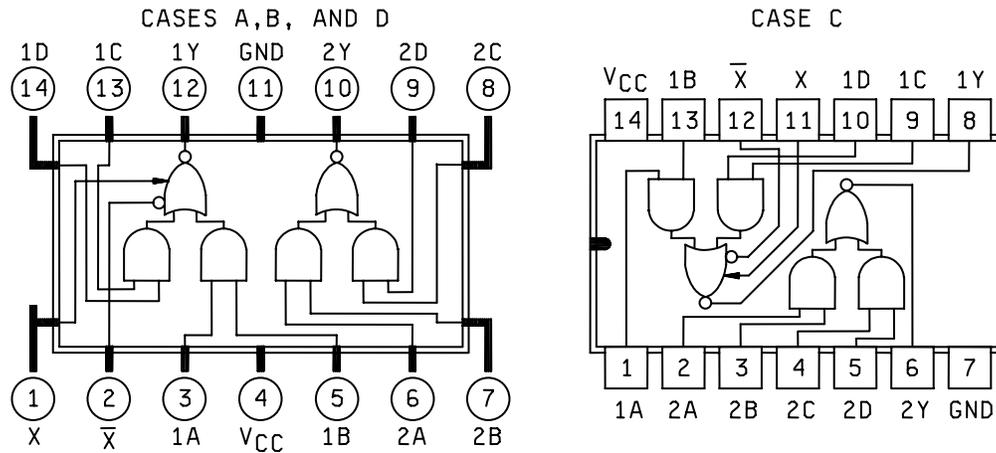
- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, 6, 7, and 8 shall be omitted.

4.4.2 Group B inspection. Group B inspection shall be in accordance with table II of MIL-PRF-38535.

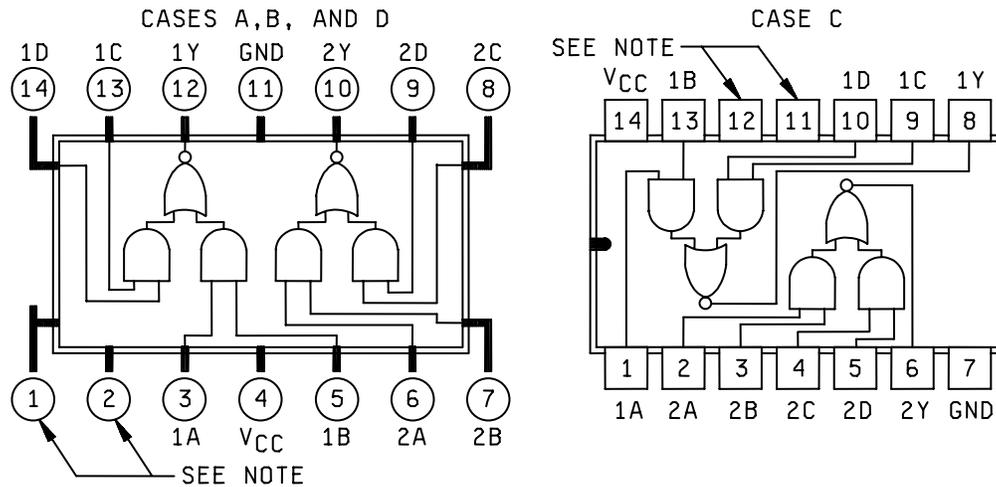
4.4.3 Group C inspection. Group C inspection shall be in accordance with table IV of MIL-PRF-38535 and as follows:

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Subgroups 3 and 4 shall be added to group C inspection parameters for class B devices and shall consist of the tests, conditions, and limits specified for subgroups 10 and 11 of group A. The sample size series number shall be 5 (45 devices accept on 0).
- c. The steady-state life test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.

DEVICE TYPE 01



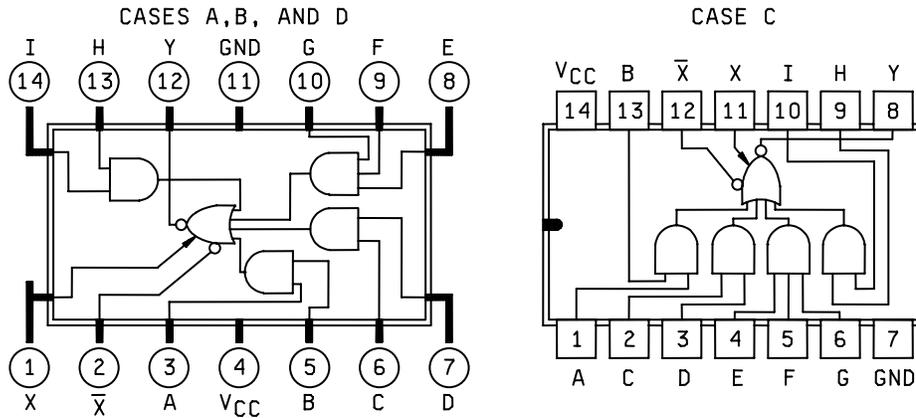
DEVICE TYPE 02



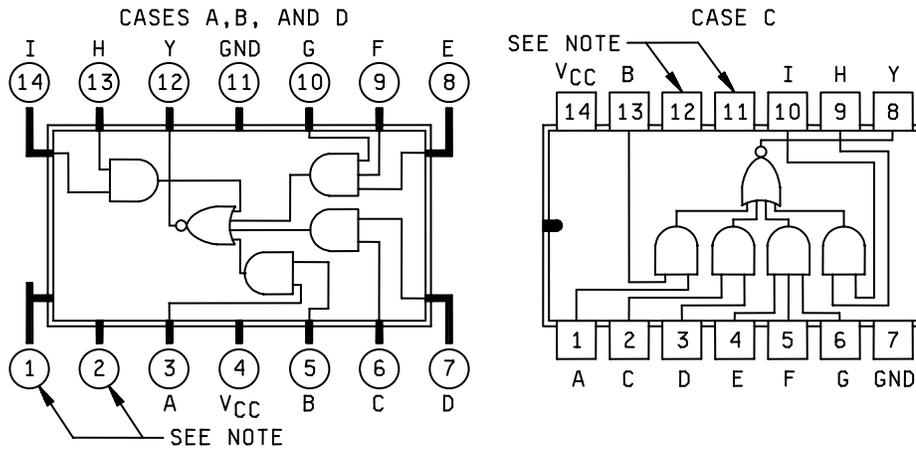
NOTE: Do not use as external tie points since they may be electrically connected internally.

FIGURE 1. Logic diagram and terminal connections (topview).

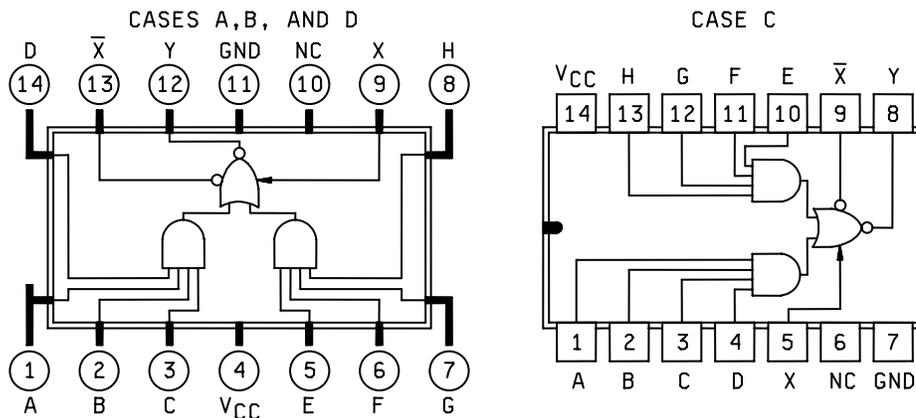
DEVICE TYPE 03



DEVICE TYPE 04



DEVICE TYPE 05



NOTE: Do not use as external tie points since they may be electrically connected internally.

FIGURE 1. Logic diagram and terminal connections (topview).- Continued.

Device type 01

TRUTH TABLE (each gate)					
Input					Output
A	B	C	D	X	Y
H	H	*	*	*	L
*	*	H	H	*	L
*	*	*	*	H	L

\* Either H or L - All other combinations of H and L at the input give H output.

Positive logic:  $Y = \overline{(AB) + (CD) + (X)}$

Device type 02

TRUTH TABLE (each gate)				
Input				Output
A	B	C	D	Y
H	H	*	*	L
*	*	H	H	L

\* Either H or L - All other combinations of H and L at the input give H output.

Positive logic:  $Y = \overline{(AB) + (CD)}$

FIGURE 2. Truth tables and logic equations.

Device type 03

TRUTH TABLE (each gate)										
Input										Output
A	B	C	D	E	F	G	H	I	X	Y
H	H	*	*	*	*	*	*	*	*	L
*	*	H	H	*	*	*	*	*	*	L
*	*	*	*	H	H	H	*	*	*	L
*	*	*	*	*	*	*	H	H	*	L
*	*	*	*	*	*	*	*	*	H	L

\* Either H or L - All other combinations of H and L at the input give H output.

Positive logic:  $Y = \overline{(AB) + (CD) + (EFG) + (HI) + X}$

Device type 04

TRUTH TABLE (each gate)										
Input										Output
A	B	C	D	E	F	G	H	I	Y	
H	H	*	*	*	*	*	*	*	L	
*	*	H	H	*	*	*	*	*	L	
*	*	*	*	H	H	H	*	*	L	
*	*	*	*	*	*	*	H	H	L	

\* Either H or L - All other combinations of H and L at the input give H output.

Positive logic:  $Y = \overline{(AB) + (CD) + (EFG) + (HI)}$

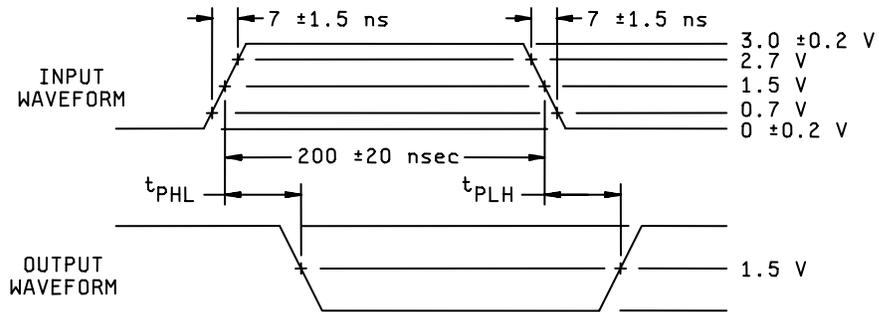
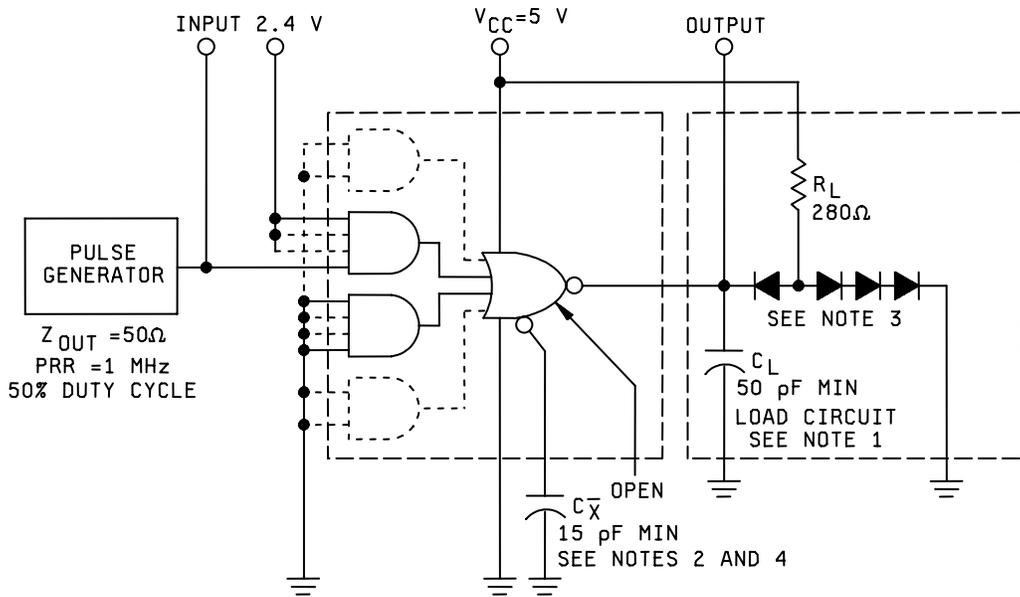
Device type 05

TRUTH TABLE (each gate)										
Input										Output
A	B	C	D	E	F	G	H	X	Y	
H	H	H	H	*	*	*	*	*	L	
*	*	*	*	H	H	H	H	*	L	
*	*	*	*	*	*	*	*	H	L	

\* Either H or L - All other combinations of H and L at the input give H output.

Positive logic:  $Y = \overline{(ABCD) + (EFGH) + X}$

FIGURE 2. Truth tables and logic equations - Continued.



NOTES:

1.  $C_L$  includes probe and jig capacitance.
2.  $C_{\bar{X}}$  includes jig capacitances. (Applies to device types 01, 03, and 05 only).
3. All diodes are 1N3064, or equivalent.
4. For  $t_{PLH1}$  and  $t_{PHL1}$ , no connection is made to  $\bar{X}$ .

FIGURE 3. Switching time test circuit.

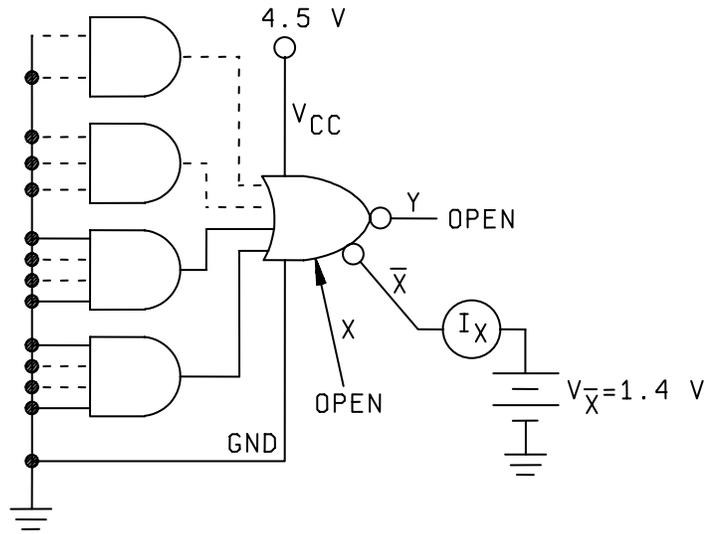


FIGURE 4. Expander current test circuit for device types 01, 03, and 05.

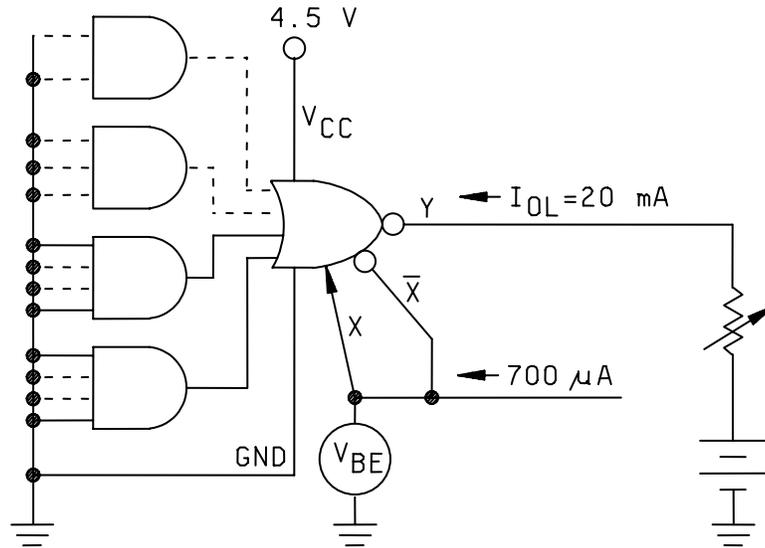


FIGURE 5. Base emitter voltage test circuit for device types 01, 03, and 05.

TABLE III. Group A inspection for device type 01.  
Terminal conditions (pins not designated are open)

Subgroup	Symbol	MIL-STD-883 method	Cases A, B, D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Test limits		Unit	
			Case C	11	12	1	14	13	2	3	4	5	6	7	8	9	10		Min	Max		
			Test no.	X	X	1A	V <sub>CC</sub>	1B	2A	2B	2C	2D	2Y	GND	1Y	1C	1D					
1 T <sub>C</sub> = +25°C	V <sub>OH</sub>	3006	1			0.8 V	4.5 V	5.5 V						GND	-0.5 mA	GND	GND	1Y	2.4		V	
		"	2			5.5 V	"	0.8 V						"	"	GND	GND	1Y	"		"	
		"	3			GND	"	GND						"	"	0.8 V	5.5 V	1Y	"		"	
		"	4			"	"	"						"	"	5.5 V	0.8 V	1Y	"		"	
		"	5	0.32 mA	-0.32 mA	"	"	"						"	"	GND	GND	1Y	"		"	
		"	5a 1/	0.4 V	-0.32 mA	"	"	"						"	"	GND	GND	1Y	"		"	
		"	6							0.8 V	5.5 V	GND	GND	-0.5 mA	"	"			2Y	"		"
		"	7							5.5 V	0.8 V	GND	GND	"	"	"			2Y	"		"
		"	8							GND	GND	0.8 V	5.5 V	"	"	"			2Y	"		"
	"	9							GND	GND	5.5 V	0.8 V	"	"	"			2Y	"		"	
	V <sub>OL</sub>	3007	10			2.0 V	"	2.0 V						"	20 mA	GND	GND	1Y		0.4	"	
		"	11			GND	"	GND						"	"	2.0 V	2.0 V	1Y		"	"	
		"	12	0.47 mA	2/	"	"	"						"	"	GND	GND	1Y		"	"	
		"	12a 1/	3.8 mA	1.3 V	"	"	"						"	"	GND	GND	1Y		"	"	
		"	13						2.0 V	2.0 V	GND	GND	20 mA	"	"			2Y		"	"	
	I <sub>IL</sub>	3009	15			0.4 V	5.5 V	5.5 V						"				1A	-1.0	-2.0	mA	
		"	16			5.5 V	"	0.4 V						"				1B	"	"	"	
		"	17				"							"				1C	"	"	"	
		"	18				"							"		0.4 V	5.5 V	1D	"	"	"	
		"	19				"			0.4 V	5.5 V			"		5.5 V	0.4 V	2A	"	"	"	
		"	20				"			5.5 V	0.4 V			"				2B	"	"	"	
	I <sub>IH1</sub>	3010	23			2.4 V	"	GND						"				1A		50	μA	
		"	24			GND	"	2.4 V						"				1B		"	"	
		"	25				"							"				1C		"	"	
		"	26				"							"		2.4 V	GND	1D		"	"	
		"	27				"			2.4 V	GND			"		GND	2.4 V	2A		"	"	
		"	28				"			GND	2.4 V			"				2B		"	"	
		"	29				"					2.4 V	GND	"				2C		"	"	
		"	30				"					GND	2.4 V	"				2D		"	"	

See notes at end of device type 01.

TABLE III. Group A inspection for device type 01 – Continued.  
Terminal conditions (pins not designated are open)

Subgroup	Symbol	MIL-STD-883 method	Cases A, B, D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Test limits		Unit
			Case C	11	12	1	14	13	2	3	4	5	6	7	8	9	10		Min	Max	
			Test no.	X	X	1A	V <sub>CC</sub>	1B	2A	2B	2C	2D	2Y	GND	1Y	1C	1D				
1 T <sub>C</sub> = +25°C	I <sub>IH2</sub>	3010	31			5.5 V	5.5 V	GND						GND				1A		100	μA
		"	32			GND	"	5.5 V						"				1B		"	"
		"	33				"							"				1C		"	"
		"	34				"							"	5.5 V	GND		1D		"	"
		"	35				"			5.5 V	GND			"	GND	5.5 V		2A		"	"
		"	36				"			GND	5.5 V			"				2B		"	"
		"	37				"					5.5 V	GND		"			2C		"	"
		"	38				"					GND	5.5 V		"			2D		"	"
	I <sub>OS</sub>	3011	39			GND	"	GND						"	GND	GND	GND	1Y	-40	-100	mA
		3011	40				"		GND	GND	GND	GND	GND	"				2Y	-40	-100	"
	I <sub>CCL</sub>	3005	41			5.5 V	"	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V		"		5.5 V	5.5 V	V <sub>CC</sub>		24	"
	I <sub>CCH</sub>	3005	42			GND	"	GND	GND	GND	GND	GND		"		GND	GND	V <sub>CC</sub>		13	"
	V <sub>IC</sub>			43			-12 mA	4.5 V										1A		-1.5	V
				44			"	"	-12 mA						"			1B		"	"
			45			"	"						"				1C		"	"	
			46			"	"						"				1D		"	"	
			47			"	"		-12 mA				"				2A		"	"	
			48			"	"			-12 mA			"				2B		"	"	
			49			"	"				-12 mA		"				2C		"	"	
			50			"	"					-12 mA		"			2D		"	"	
I <sub>X</sub>	3/	51		1.4 V	GND	"	GND	GND	GND	GND	GND		"		GND	GND	X		-5.85	mA	
V <sub>BE</sub>	4/	52	0.7 mA		GND	"	GND	GND	GND	GND	GND		"	20 mA	GND	GND	X		1.1	V	
2	Same tests, terminal conditions, and limits as for subgroup 1, except T <sub>C</sub> = +125°C and V <sub>IC</sub> tests are omitted.																				
3	Same tests, terminal conditions, and limits as for subgroup 1, except T <sub>C</sub> = -55°C and V <sub>IC</sub> tests are omitted.																				

See notes at end of device type 01.

TABLE III. Group A inspection for device type 01 – Continued.  
Terminal conditions (pins not designated are open)

Subgroup	Symbol	MIL-STD-883 method	Cases A, B, D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Test limits		Unit
			Case C	11	12	1	14	13	2	3	4	5	6	7	8	9	10		Min	Max	
			Test no.	X	$\bar{X}$	1A	V <sub>CC</sub>	1B	2A	2B	2C	2D	2Y	GND	1Y	1C	1D				
9 T <sub>C</sub> = +25°C	t <sub>PHL1</sub>	3003 Fig. 4	53			IN	5.0 V	2.4 V						GND	OUT	GND	GND	1A to 1Y	2	13	ns
			54					"		IN	2.4 V	GND	GND	OUT	"				2A to 2Y	"	13
	t <sub>PLH1</sub>	"	55			IN	"	2.4 V						"	OUT	GND	GND	1A to 1Y	"	15	"
			56			IN	"	2.4 V						"	OUT	GND	GND	1A to 1Y	"	14	"
10 T <sub>C</sub> = +125°C	t <sub>PHL1</sub>	"	57				"		IN	2.4 V	GND	GND	OUT	"				2A to 2Y	"	14	"
			58			IN	"	2.4 V						"	OUT	GND	GND	1A to 1Y	"	18	"
	t <sub>PHL2</sub>	"	59			IN	"	2.4 V					"	OUT	GND	GND	1A to 1Y	"	"	"	
			60				"		IN	2.4 V	GND	GND	OUT	"				2A to 2Y	"	"	"
11	t <sub>PLH2</sub>	"	61			IN	"	2.4 V					"	OUT	GND	GND	1A to 1Y	"	22	"	
			62			IN	"	2.4 V					"	OUT	GND	GND	1A to 1Y	"	18	"	
	t <sub>PLH1</sub>	"	63				"		IN	2.4 V	GND	GND	OUT	"				2A to 2Y	"	18	"
			64			IN	"	2.4 V					"	OUT	GND	GND	1A to 1Y	"	26	"	
Same tests, terminal conditions, and limits as for subgroup 10, except T <sub>C</sub> = -55°C.																					

1/ At the manufacturer's option, the high and low level output voltage tests for the expanded inputs may be verified by performing either tests 5 and 12 or 5a and 12a.

2/ R<sub>1</sub> = 68 ohms between X and  $\bar{X}$ .

3/ See figure 5.

4/ See figure 6.

TABLE III. Group A inspection for device type 02.  
Terminal conditions (pins not designated are open)

Subgroup	Symbol	MIL-STD-883 method	Cases A, B, D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Test limits		Unit
			Case C	11	12	1	14	13	2	3	4	5	6	7	8	9	10		Min	Max	
			Test no.	NC	NC	1A	V <sub>CC</sub>	1B	2A	2B	2C	2D	2Y	GND	1Y	1C	1D				
1 T <sub>C</sub> = +25°C	V <sub>OH</sub>	3006	1			0.8 V	4.5 V	5.5 V						GND	-0.5 mA	GND	GND	1Y	2.4		V
		"	2			5.5 V	"	0.8 V						"	"	GND	GND	1Y	"		"
		"	3			GND	"	GND						"	"	0.8 V	5.5 V	1Y	"		"
		"	4			GND	"	GND						"	"	5.5 V	0.8 V	1Y	"		"
		"	5				"				0.8 V	5.5 V	GND	GND	-0.5 mA	"		2Y	"		"
		"	6				"				5.5 V	0.8 V	GND	GND	"	"		2Y	"		"
		"	7				"				GND	GND	0.8 V	5.5 V	"	"		2Y	"		"
		"	8				"				GND	GND	5.5 V	0.8 V	"	"		2Y	"		"
	V <sub>OL</sub>	3007	9			2.0 V	"	2.0 V						"	20 mA	GND	GND	1Y		0.4	"
		"	10			GND	"	GND						"	20 mA	2.0 V	2.0 V	1Y		"	"
		"	11				"		2.0 V	2.0 V	GND	GND	20 mA	"	"			2Y		"	"
		"	12				"		GND	GND	2.0 V	2.0 V	20 mA	"	"			2Y		"	"
	I <sub>IL</sub>	3009	13			0.4 V	5.5 V	5.5 V						"				1A	-1.0	-2.0	mA
		"	14			5.5 V	"	0.4 V						"				1B	"	"	"
		"	15				"							"		0.4 V	5.5 V	1C	"	"	"
		"	16				"							"		5.5 V	0.4 V	1D	"	"	"
		"	17				"		0.4 V	5.5 V				"				2A	"	"	"
		"	18				"		5.5 V	0.4 V				"				2B	"	"	"
		"	19				"				0.4 V	5.5 V		"				2C	"	"	"
		"	20				"				5.5 V	0.4 V		"				2D	"	"	"
	I <sub>IH1</sub>	3010	21			2.4 V	"	GND						"				1A		50	μA
		"	22			GND	"	2.4 V						"				1B		"	"
		"	23				"							"				1C		"	"
		"	24				"							"		2.4 V	GND	1D		"	"
		"	25				"		2.4 V	GND				"		GND	2.4 V	2A		"	"
		"	26				"		GND	2.4 V				"				2B		"	"
		"	27				"				2.4 V	GND		"				2C		"	"
		"	28				"				GND	2.4 V		"				2D		"	"
	I <sub>IH2</sub>	"	29			5.5 V	"	GND						"				1A		100	"
		"	30			GND	"	5.5 V						"				1B		"	"
		"	31				"							"				1C		"	"
		"	32				"							"		5.5 V	GND	1D		"	"
		"	33				"		5.5 V	GND				"		GND	5.5 V	2A		"	"
		"	34				"			5.5 V				"				2B		"	"
		"	35				"				5.5 V	GND		"				2C		"	"
		"	36				"				GND	5.5 V		"				2D		"	"

TABLE III. Group A inspection for device type 02 – Continued.  
Terminal conditions (pins not designated are open)

Subgroup	Symbol	MIL-STD-883 method	Cases A, B, D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Test limits		Unit	
			Case C	11	12	1	14	13	2	3	4	5	6	7	8	9	10		Min	Max		
			Test no.	NC	NC	1A	V <sub>CC</sub>	1B	2A	2B	2C	2D	2Y	GND	1Y	1C	1D					
1 T <sub>C</sub> = +25°C	I <sub>OS</sub>	3011	37			GND	5.5 V	GND						GND	GND	GND	GND	1Y	-40	-100	mA	
		3011	38				"		GND	GND	GND	GND	GND	"				2Y	-40	-100	"	
	I <sub>CCL</sub>	3005	39			5.5 V	"	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V		"		5.5 V	5.5 V	V <sub>CC</sub>		24	"	
	I <sub>CCH</sub>	3005	40			GND	"	GND	GND	GND	GND	GND		"		GND	GND	V <sub>CC</sub>		13	"	
	V <sub>IC</sub>		41			-12 mA	4.5 V		-12 mA						"				1A		-1.5	V
			42				"								"				1B		"	"
			43				"								"				1C		"	"
			44				"								"				1D		"	"
			45				"			-12 mA					"				2A		"	"
		46				"				-12 mA				"				2B		"	"	
		47				"					-12 mA			"				2C		"	"	
	48				"						-12 mA		"				2D		"	"		
2	Same tests, terminal conditions, and limits as for subgroup 1, except T <sub>C</sub> = +125°C and V <sub>IC</sub> tests are omitted.																					
3	Same tests, terminal conditions, and limits as for subgroup 1, except T <sub>C</sub> = -55°C and V <sub>IC</sub> tests are omitted.																					
9 T <sub>C</sub> = +25°C	t <sub>PHL1</sub>	3003	49			IN	5.0 V	2.4 V						GND	OUT	GND	GND	1A to 1Y	2	13	ns	
		Fig. 4	50				"		IN	2.4 V	GND	GND	OUT	"	OUT	GND	GND	2A to 2Y	"	13	"	
	t <sub>PLH1</sub>	"	51			IN	"	2.4 V						"	OUT	GND	GND	1A to 1Y	"	14	"	
		"	52				"		IN	2.4 V	GND	GND	OUT	"	OUT	GND	GND	2A to 2Y	"	14	"	
10 T <sub>C</sub> = +125°C	t <sub>PHL1</sub>	"	53			IN	"	2.4 V						"	OUT	GND	GND	1A to 1Y	"	18	"	
		"	54				"		IN	2.4 V	GND	GND	OUT	"	OUT	GND	GND	2A to 2Y	"	"	"	
	t <sub>PLH1</sub>	"	55			IN	"	2.4 V						"	OUT	GND	GND	1A to 1Y	"	"	"	
		"	56				"		IN	2.4 V	GND	GND	OUT	"	OUT	GND	GND	2A to 2Y	"	"	"	
11	Same tests, terminal conditions, and limits as for subgroup 10, except T <sub>C</sub> = -55°C.																					

TABLE III. Group A inspection for device type 03.  
Terminal conditions (pins not designated are open)

Subgroup	Symbol	MIL-STD-883 method	Cases A, B, D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Test limits		Unit	
			Case C	11	12	1	14	13	2	3	4	5	6	7	8	9	10		Min	Max		
			Test no.	X	$\bar{X}$	A	V <sub>CC</sub>	B	C	D	E	F	G	GND	Y	H	I					
1 T <sub>C</sub> = +25°C	V <sub>OH</sub>	3006	1			0.8 V	4.5 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	5.5 V	GND	-0.5 mA	0.8 V	5.5 V	Y	2.4		V	
		"	2			5.5 V	"	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	"	"	5.5 V	0.8 V	Y	"		"	
		"	3			5.5 V	"	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	"	"	5.5 V	0.8 V	Y	"		"
		"	4	0.32 mA	-0.32 mA	GND	"	GND	"	"	GND	GND	Y	"		"						
		"	4a 1/	0.4 V	-0.32 mA	GND	"	GND	GND	GND	GND	GND	"	"	"	"	"	"	Y	"		"
	V <sub>OL</sub>	3007	5			2.0 V	"	2.0 V	GND	GND	GND	"	"	"	"	20 mA	"	"	Y		0.4	"
		"	6			GND	"	GND	2.0 V	2.0 V	"	"	"	"	"	"	"	"	Y			"
		"	7			"	"	"	GND	GND	2.0 V	2.0 V	2.0 V	"	"	"	"	"	Y			"
		"	8			"	"	"	"	"	GND	GND	GND	"	"	"	2.0 V	2.0 V	Y			"
		"	9	0.47 mA	2/	"	"	"	"	"	"	"	"	"	"	"	GND	GND	Y			"
	I <sub>IL</sub>	3009	10			0.4 V	5.5 V	5.5 V							"				A	-1.0	-2.0	mA
		"	11			5.5 V	"	0.4 V							"				B	"	"	"
		"	12						0.4 V	5.5 V					"				C	"	"	"
		"	13						"	"					"				D	"	"	"
		"	14						"	"	0.4 V	5.5 V	5.5 V	"	"				E	"	"	"
		"	15						"	"	5.5 V	0.4 V	5.5 V	"	"				F	"	"	"
		"	16						"	"	5.5 V	5.5 V	0.4 V	"	"				G	"	"	"
		"	17						"	"	"	"	"	"	"		0.4 V	5.5 V	H	"	"	"
		"	18						"	"	"	"	"	"	"		5.5 V	0.4 V	I	"	"	"
	I <sub>IH1</sub>	3010	19			2.4 V	"	GND							"				A		50	μA
		"	20			GND	"	2.4 V							"				B		"	"
		"	21				"		2.4 V	GND					"				C		"	"
		"	22				"		"	2.4 V					"				D		"	"
		"	23				"		"	"	2.4 V	GND	GND		"				E		"	"
		"	24				"		"	"	GND	2.4 V	GND		"				F		"	"
		"	25				"		"	"	GND	GND	2.4 V		"				G		"	"
		"	26				"		"	"	"	"	"		"		2.4 V	GND	H		"	"
		"	27				"		"	"	"	"	"		"		GND	2.4 V	I		"	"
	I <sub>IH2</sub>	"	28			5.5 V	"	GND							"				A		100	"
		"	29			GND	"	5.5 V							"				B		"	"
		"	30				"		5.5 V	GND					"				C		"	"
		"	31				"		"	"					"				D		"	"
		"	32				"		"	"	5.5 V	GND	GND		"				E		"	"
		"	33				"		"	"	GND	5.5 V	GND		"				F		"	"
		"	34				"		"	"	GND	GND	5.5 V		"				G		"	"
		"	35				"		"	"	"	"	"		"		5.5 V	GND	H		"	"
"		36				"		"	"	"	"	"		"		GND	5.5 V	I		"	"	

See notes at end of device type 03.

TABLE III. Group A inspection for device type 03 – Continued.  
Terminal conditions (pins not designated are open)

Subgroup	Symbol	MIL-STD-883 method	Cases A, B, D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Test limits		Unit	
			Case C	11	12	1	14	13	2	3	4	5	6	7	8	9	10		Min	Max		
			Test no.	X	$\bar{X}$	A	V <sub>CC</sub>	B	C	D	E	F	G	GND	Y	H	I					
1 T <sub>C</sub> = +25°C	I <sub>OS</sub>	3011	37			GND	5.5 V	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	Y	-40	-100	mA	
	I <sub>CCL</sub>	3005	38			5.5 V	"	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	"		5.5 V	5.5 V	V <sub>CC</sub>		14	"	
	I <sub>CCH</sub>	3005	39			GND	"	GND	GND	GND	GND	GND	GND	"		GND	GND	V <sub>CC</sub>		11	"	
	V <sub>IC</sub>			40			-12 mA	4.5 V											A		-1.5	V
				41				"	-12 mA										B		"	"
				42				"		-12 mA									C		"	"
				43				"			-12 mA								D		"	"
				44				"				-12 mA							E		"	"
				45				"					-12 mA						F		"	"
				46				"						-12 mA					G		"	"
			47				"									-12 mA		H		"	"	
		48				"										-12 mA	I		"	"		
	I <sub>X</sub>	3/	49		1.4 V	GND	"	GND	GND	GND	GND	GND	GND	"		GND	GND	$\bar{X}$		-5.85	mA	
	V <sub>BE</sub>	4/	50	0.7 mA		GND	"	GND	GND	GND	GND	GND	GND	"	20 mA	GND	GND	X		1.1	V	
2	Same tests, terminal conditions, and limits as for subgroup 1, except T <sub>C</sub> = +125°C and V <sub>IC</sub> tests are omitted.																					
3	Same tests, terminal conditions, and limits as for subgroup 1, except T <sub>C</sub> = -55°C and V <sub>IC</sub> tests are omitted.																					
9 T <sub>C</sub> = +25°C	t <sub>PHL1</sub>	3003	51			IN	5.0 V	2.4 V	GND	GND	GND	GND	GND	GND	OUT	GND	GND	A to Y	2	13	ns	
	t <sub>PLH1</sub>	Fig. 4	52			"	"	"	"	"	"	"	"	"	"	"	"	A to Y	"	14	"	
	t <sub>PHL2</sub>	"	53			"	"	"	"	"	"	"	"	"	"	"	"	A to Y	"	15	"	
	t <sub>PLH2</sub>	"	54			"	"	"	"	"	"	"	"	"	"	"	"	A to Y	"	18	"	
10 T <sub>C</sub> = +125°C	t <sub>PHL1</sub>	"	55			"	"	"	"	"	"	"	"	"	"	"	"	A to Y	"	"	"	
	t <sub>PLH1</sub>	"	56			"	"	"	"	"	"	"	"	"	"	"	"	A to Y	"	"	"	
	t <sub>PHL2</sub>	"	57			"	"	"	"	"	"	"	"	"	"	"	"	A to Y	"	22	"	
	t <sub>PLH2</sub>	"	58			"	"	"	"	"	"	"	"	"	"	"	"	A to Y	"	26	"	
11	Same tests, terminal conditions, and limits as for subgroup 10, except T <sub>C</sub> = -55°C.																					

1/ At the manufacturer's option, the high and low level output voltage tests for the expanded inputs may be verified by performing either tests 4 and 9 or 4a and 9a.

2/ R<sub>1</sub> = 68 ohms between X and  $\bar{X}$ .

3/ See figure 5.

4/ See figure 6.

TABLE III. Group A inspection for device type 04.  
Terminal conditions (pins not designated are open)

Subgroup	Symbol	MIL-STD-883 method	Cases A, B, D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Test limits		Unit	
			Case C	11	12	1	14	13	2	3	4	5	6	7	8	9	10		Min	Max		
			Test no.	NC	NC	A	V <sub>CC</sub>	B	C	D	E	F	G	GND	Y	H	I					
1 T <sub>C</sub> = +25°C	V <sub>OH</sub>	3006	1			0.8 V	4.5 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	5.5 V	GND	-0.5 mA	0.8 V	5.5 V	Y	2.4		V	
		"	2			5.5 V	"	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	"	"	5.5 V	0.8 V	Y	"		"	
		"	3			5.5 V	"	0.8 V	5.5 V	0.8 V	5.5 V	0.8 V	5.5 V	"	"	5.5 V	0.8 V	Y	"		"	
	V <sub>OL</sub>	3007	4			2.0 V	"	2.0 V	GND	GND	GND	GND	GND	GND	"	20 mA	GND	GND	Y		0.4	"
		"	5			GND	"	GND	2.0 V	"	"	"	"	"	Y		"	"				
		"	6			"	"	"	GND	GND	2.0 V	2.0 V	2.0 V	"	"	"	"	"	Y		"	"
		"	7			"	"	"	GND	GND	GND	GND	GND	"	"	2.0 V	2.0 V	"	Y		"	"
	I <sub>IL</sub>	3009	8			0.4 V	5.5 V	5.5 V							"				A	-1.0	-2.0	mA
		"	9			5.5 V	"	0.4 V							"				B	"	"	"
		"	10				"		0.4 V	5.5 V					"				C	"	"	"
		"	11				"		5.5 V	0.4 V					"				D	"	"	"
		"	12				"				0.4 V	5.5 V	5.5 V		"				E	"	"	"
		"	13				"				5.5 V	0.4 V	5.5 V		"				F	"	"	"
		"	14				"				5.5 V	5.5 V	0.4 V		"				G	"	"	"
		"	15				"								"		0.4 V	5.5 V	H	"	"	"
		"	16				"								"		5.5 V	0.4 V	I	"	"	"
	I <sub>IH1</sub>	3010	17			2.4 V	"	GND							"				A		50	μA
		"	18			GND	"	2.4 V							"				B		"	"
		"	19				"		2.4 V	GND					"				C		"	"
		"	20				"		GND	2.4 V					"				D		"	"
		"	21				"				2.4 V	GND	GND		"				E		"	"
		"	22				"				GND	2.4 V	GND		"				F		"	"
		"	23				"				GND	GND	2.4 V		"				G		"	"
		"	24				"								"		2.4 V	GND	H		"	"
		"	25				"								"		GND	2.4 V	I		"	"
	I <sub>IH2</sub>	"	26			5.5 V	"	GND							"				A		100	"
		"	27			GND	"	5.5 V							"				B		"	"
		"	28				"		5.5 V	GND					"				C		"	"
		"	29				"		GND	5.5 V					"				D		"	"
		"	30				"				5.5 V	GND	GND		"				E		"	"
		"	31				"				GND	5.5 V	GND		"				F		"	"
		"	32				"				GND	GND	5.5 V		"				G		"	"
		"	33				"								"		5.5 V	GND	H		"	"
		"	34				"								"		GND	5.5 V	I		"	"

TABLE III. Group A inspection for device type 04 – Continued.  
Terminal conditions (pins not designated are open)

Subgroup	Symbol	MIL-STD-883 method	Cases A, B, D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Test limits		Unit	
			Case C	11	12	1	14	13	2	3	4	5	6	7	8	9	10		Min	Max		
			Test no.	NC	NC	A	V <sub>CC</sub>	B	C	D	E	F	G	GND	Y	H	I					
1 T <sub>C</sub> = +25°C	I <sub>OS</sub>	3011	35			GND	5.5 V	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	Y	-40	-100	mA	
	I <sub>CCL</sub>	3005	36			5.5 V	"	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	5.5 V	"		5.5 V	5.5 V	V <sub>CC</sub>		14	"	
	I <sub>CCH</sub>	3005	37			GND	"	GND	GND	GND	GND	GND	GND	"		GND	GND	V <sub>CC</sub>		11	"	
	V <sub>IC</sub>			38			-12 mA	4.5 V											A		-1.5	V
				39				"	-12 mA										B		"	"
				40				"		-12 mA									C		"	"
				41				"			-12 mA								D		"	"
				42				"				-12 mA							E		"	"
				43				"					-12 mA						F		"	"
				44				"						-12 mA					G		"	"
		45				"											H		"	"		
		46				"											I		"	"		
2	Same tests, terminal conditions, and limits as for subgroup 1, except T <sub>C</sub> = +125°C and V <sub>IC</sub> tests are omitted.																					
3	Same tests, terminal conditions, and limits as for subgroup 1, except T <sub>C</sub> = -55°C and V <sub>IC</sub> tests are omitted.																					
9 T <sub>C</sub> = +25°C	t <sub>PHL1</sub>	3003	47			IN	5.0 V	2.4 V	GND	GND	GND	GND	GND	GND	OUT	GND	GND	A to Y	2	13	ns	
	t <sub>PLH1</sub>	Fig. 4	48			"	"	"	"	"	"	"	"	"	"	"	"	A to Y	"	14	"	
10 T <sub>C</sub> = +125°C	t <sub>PHL1</sub>	"	49			"	"	"	"	"	"	"	"	"	"	"	"	A to Y	"	18	"	
	t <sub>PLH1</sub>	"	50			"	"	"	"	"	"	"	"	"	"	"	"	A to Y	"	18	"	
11	Same tests, terminal conditions, and limits as for subgroup 10, except T <sub>C</sub> = -55°C.																					

TABLE III. Group A inspection for device type 05.  
Terminal conditions (pins not designated are open)

Subgroup	Symbol	MIL-STD-883 method	Cases A, B, D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Test limits		Unit	
			Case C	1	2	3	14	10	11	12	13	5	6	7	8	9	4		Min	Max		
			Test no.	A	B	C	V <sub>CC</sub>	E	F	G	H	X	NC	GND	Y	$\bar{X}$	D					
1 T <sub>C</sub> = +25°C	V <sub>OH</sub>	3006	1	0.8 V	5.5 V	5.5 V	4.5 V	GND	GND	GND	GND			GND	-0.5 mA		5.5 V	Y	2.4		V	
		"	2	GND	GND	GND	"	0.8 V	5.5 V	5.5 V	5.5 V			"	"		GND	Y	"		"	
		"	3	"	"	"	"	GND	GND	GND	GND	0.32mA			"	"	-0.32mA	"	Y	"		"
				3a 1/	"	"	"	"	"	"	"	0.4 V			"	"	-0.32mA	"	Y	"		"
	V <sub>OL</sub>	3007	4	2.0 V	2.0 V	2.0 V	"	"	"	"	"	"			"	20 mA		2.0 V	Y		0.4	"
		"	5	GND	GND	GND	"	2.0 V	2.0 V	2.0 V	2.0 V			"	"	"	"	GND	Y	"	"	"
		"	6	"	"	"	"	GND	GND	GND	GND	0.47mA			"	"	<u>2/</u>	"	Y	"	"	"
		"	6a 1/	"	"	"	"	GND	GND	GND	GND	3.8 mA			"	"	1.3 V	"	Y	"	"	"
	I <sub>IL</sub>	3009	7	0.4 V	5.5 V	5.5 V	5.5 V								"			5.5 V	A	-1.0	-2.0	mA
		"	8	5.5 V	0.4 V	5.5 V	"								"			"	B	"	"	"
		"	9	"	5.5 V	0.4 V	"								"			"	C	"	"	"
		"	10	"	5.5 V	5.5 V	"								"			0.4 V	D	"	"	"
		"	11				"	0.4 V	5.5 V	5.5 V	5.5 V				"				E	"	"	"
		"	12				"	5.5 V	0.4 V	5.5 V	"				"				F	"	"	"
		"	13				"	"	5.5 V	0.4 V	"				"				G	"	"	"
		"	14				"	"	5.5 V	5.5 V	0.4 V				"				H	"	"	"
	I <sub>IH1</sub>	3010	15	2.4 V	GND	GND	"								"			GND	A		50	μA
		"	16	GND	2.4 V	GND	"								"			"	B		"	"
		"	17	"	GND	2.4 V	"								"			"	C		"	"
		"	18	"	GND	GND	"								"			2.4 V	D		"	"
		"	19				"	2.4 V	GND	GND	GND				"				E		"	"
		"	20				"	GND	2.4 V	GND	"				"				F		"	"
		"	21				"	"	GND	2.4 V	"				"				G		"	"
		"	22				"	"	GND	GND	2.4 V				"				H		"	"
	I <sub>IH2</sub>	"	23	5.5 V	GND	GND	"								"			GND	A		100	"
		"	24	GND	5.5 V	GND	"								"			"	B		"	"
		"	25	"	GND	5.5 V	"								"			"	C		"	"
		"	26	"	GND	GND	"								"			5.5 V	D		"	"
		"	27				"	5.5 V	GND	GND	GND				"				E		"	"
		"	28				"	GND	5.5 V	GND	"				"				F		"	"
"		29				"	"	GND	5.5 V	"				"				G		"	"	
"		30				"	"	GND	GND	5.5 V				"				H		"	"	

See footnotes at end of table.

TABLE III. Group A inspection for device type 05 – Continued.  
Terminal conditions (pins not designated are open)

Subgroup	Symbol	MIL-STD-883 method	Cases A, B, D	1	2	3	4	5	6	7	8	9	10	11	12	13	14	Measured terminal	Test limits		Unit	
			Case C	1	2	3	14	10	11	12	13	5	6	7	8	9	4		Min	Max		
			Test no.	A	B	C	V <sub>CC</sub>	E	F	G	H	X	NC	GND	Y	$\bar{X}$	D					
1 T <sub>C</sub> = +25°C	I <sub>OS</sub>	3011	31	GND	GND	GND	5.5 V	GND	GND	GND	GND			GND	GND		GND	Y	-40	-100	mA	
	I <sub>CC</sub> L	3005	32	5.5 V	5.5 V	5.5 V	"	5.5 V	5.5 V	5.5 V	5.5 V			"			5.5 V	V <sub>CC</sub>		12	"	
	I <sub>CC</sub> H	3005	33	GND	GND	GND	"	GND	GND	GND	GND			"			GND	V <sub>CC</sub>		6.4	"	
	V <sub>IC</sub>			34	-12 mA			4.5 V							"				A		-1.5	V
				35		-12 mA		"							"				B		"	"
				36			-12 mA	"							"				C		"	"
				37				"							"				D		"	"
				38				"	-12 mA						"				E		"	"
				39				"		-12 mA					"				F		"	"
			40				"			-12 mA				"				G		"	"	
		41				"				-12 mA			"				H		"	"		
	I <sub>X</sub>	2/	42	GND	GND	GND	"	GND	GND	GND	GND			"		1.4 V	GND	$\bar{X}$		-5.85	mA	
	V <sub>BE</sub>	3/	43	GND	GND	GND	"	GND	GND	GND	GND	0.7 mA		"	20 mA		GND	X		1.1	V	
2	Same tests, terminal conditions, and limits as for subgroup 1, except T <sub>C</sub> = +125°C and V <sub>IC</sub> tests are omitted.																					
3	Same tests, terminal conditions, and limits as for subgroup 1, except T <sub>C</sub> = -55°C and V <sub>IC</sub> tests are omitted.																					
9 T <sub>C</sub> = +25°C	t <sub>PH</sub> L1	3003	44	IN	2.4 V	2.4 V	5.0 V	GND	GND	GND	GND			GND	OUT		2.4 V	A to Y	2	13	ns	
	t <sub>PL</sub> H1	Fig. 4	45	"	"	"	"	"	"	"	"			"	"		"	A to Y	"	14	"	
	t <sub>PH</sub> L2	"	46	"	"	"	"	"	"	"	"			"	"		"	A to Y	"	15	"	
	t <sub>PL</sub> H2	"	47	"	"	"	"	"	"	"	"			"	"		"	A to Y	"	18	"	
10 T <sub>C</sub> = +125°C	t <sub>PH</sub> L1	"	48	"	"	"	"	"	"	"	"			"	"		"	A to Y	"	"	"	
	t <sub>PL</sub> H1	"	49	"	"	"	"	"	"	"	"			"	"		"	A to Y	"	"	"	
	t <sub>PH</sub> L2	"	50	"	"	"	"	"	"	"	"			"	"		"	A to Y	"	22	"	
	t <sub>PL</sub> H2	"	51	"	"	"	"	"	"	"	"			"	"		"	A to Y	"	26	"	
11	Same tests, terminal conditions, and limits as for subgroup 10, except T <sub>C</sub> = -55°C.																					

1/ At the manufacturer's option, the high and low level output voltage tests for the expanded inputs may be verified by performing either tests 3 and 6 or 3a and 6a.

2/ R<sub>1</sub> = 68 ohms between X and  $\bar{X}$ .

3/ See figure 5.

4/ See figure 6.

4.4.4 Group D inspection. Group D inspection shall be in accordance with table V of MIL-PRF-38535. End-point electrical parameters shall be as specified in table II herein.

4.5 Methods of inspection. Methods of inspection shall be specified as follows:

4.5.1 Voltage and current. All voltages given are referenced to the microcircuit ground terminal. Currents given are conventional and positive when flowing into the referenced terminal.

## 5. PACKAGING

5.1 Packaging requirements. For acquisition purposes, the packaging requirements shall be as specified in the contract or order (see 6.2). When packaging of materiel is to be performed by DoD or in-house contractor personnel, these personnel need to contact the responsible packaging activity to ascertain packaging requirements. Packaging requirements are maintained by the Inventory Control Point's packaging activity within the Military Service or Defense Agency, or within the military service's system command. Packaging data retrieval is available from the managing Military Department's or Defense Agency's automated packaging files, CD-ROM products, or by contacting the responsible packaging activity.

## 6. NOTES

(This section contains information of a general or explanatory nature that may be helpful, but it is not mandatory)

6.1 Intended use. Microcircuits conforming to this specification are intended for logistic support of existing equipment.

6.2 Acquisition requirements. Acquisition documents should specify the following:

- a. Title, number, and date of the specification.
- b. PIN and compliance identifier, if applicable (see 1.2).
- c. Requirements for delivery of one copy of the conformance inspection data pertinent to the device inspection lot to be supplied with each shipment by the device manufacturer, if applicable.
- d. Requirements for certificate of compliance, if applicable.
- e. Requirements for notification of change of product or process to contracting activity in addition to notification to the qualifying activity, if applicable.
- f. Requirements for failure analysis (including required test condition of method 5003 of MIL-STD-883), corrective action, and reporting of results, if applicable.
- g. Requirements for product assurance options.
- h. Requirements for special carriers, lead lengths, or lead forming, if applicable. These requirements should not affect the part number. Unless otherwise specified, these requirements will not apply to direct purchase by or direct shipment to the Government.
- i. Requirements for "JAN" marking.
- j. Packaging requirements (see 5.1).

6.3 Qualification. With respect to products requiring qualification, awards will be made only for products which are, at the time of award of contract, qualified for inclusion in Qualified Manufacturers List QML-38535 whether or not such products have actually been so listed by that date. The attention of the contractors is called to these requirements, and manufacturers are urged to arrange to have the products that they propose to offer to the Federal Government tested for qualification in order that they may be eligible to be awarded contracts or purchase orders for the products covered by this specification. Information pertaining to qualification of products may be obtained from DSCC-VQ, 3990 E. Broad Street, Columbus, Ohio 43123-1199.

6.4 Superseding information. The requirements of MIL-M-38510 have been superseded to take advantage of the available Qualified Manufacturer Listing (QML) system provided by MIL-PRF-38535. Previous references to MIL-M-38510 in this document have been replaced by appropriate references to MIL-PRF-38535. All technical requirements now consist of this specification and MIL-PRF-38535. The MIL-M-38510 specification sheet number and PIN have been retained to avoid adversely impacting existing government logistics systems and contractor's parts lists.

6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535, MIL-HDBK-1331, and as follows:

GND .....	Ground zero voltage potential
I <sub>IN</sub> .....	Current flowing into an input terminal
T <sub>C</sub> .....	Case temperature
V <sub>IN</sub> .....	Voltage level at an input terminal

6.6 Logistic support. Lead materials and finishes (see 3.4) are interchangeable. Unless otherwise specified, microcircuits acquired for Government logistic support will be acquired to device class B (see 1.2.2), lead material and finish A (see 3.4). Longer length leads and lead forming should not affect the part number.

6.7 Substitutability. The cross-reference information below is presented for the convenience of users. Microcircuits covered by this specification will functionally replace the listed generic-industry type. Generic-industry microcircuit types may not have equivalent operational performance characteristics across military temperature ranges or reliability factors equivalent to MIL-M-35810 device types and may have slight physical variations in relation to case size. The presence of this information should not be deemed as permitting substitution of generic-industry types for MIL-M-38510 types or as a waiver of any of the provisions of MIL-PRF-38535.

<u>Military device type</u>	<u>Generic-industry type</u>
01	54H50
02	54H51
03	54H53
04	54H54
05	54H55

6.8 Changes from previous issue. Marginal notations are not used in this revision to identify changes with respect to the previous issue due to the extensiveness of the changes.

Custodians:  
 Army - CR  
 Navy - EC  
 Air Force - 11  
 DLA - CC

Preparing activity:  
 DLA - CC  
 (Project 5962-2005-051)

Review activities:  
 Army - MI, SM  
 Navy - AS, CG, MC, SH, TD  
 Air Force - 03, 19, 99

NOTE: The activities listed above were interested in this document as of the date of this document. Since organizations and responsibilities can change, you should verify the currency of the information above using the ASSIST Online database at <http://assist.daps.dla.mil>.